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Substitute for form 1449A/PTO				Application Number	10/062,196
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				Filing Date	1/31/2002
				First Named Inventor	Steven Teig, et al.
				Group Art Unit	2123
				Examiner Name	Teska, Kevin
Sheet	1	of	3	Attorney Docket Number	SPLX.P0113

U.S. PATENT APPLICATIONS						
Examiner Initials	Cite No. <sup>1</sup>	U.S. Patent Application		Name of Patentee or Applicant of Cited Document	Date of Filing MM-DD-YYYY	Related Application Data (if any)
		Serial Number	Attorney Docket No.			
TUS	1.	10/335,247	CDN.P0053	Steven Teig et al.	12-31-2002	CIP of 10/062,264.
	2.	10/335,097	CDN.P0054	Steven Teig et al.	12-31-2002	CIP of 10/062,264.
	3.	10/335,248	CDN.P0055	Steven Teig et al.	12-31-2002	CIP of 10/062,264.
	4.	10/335,095	CDN.P0056	Steven Teig et al.	12-31-2002	CIP of 10/062,264.
	5.	10/334,664	CDN.P0057	Steven Teig et al.	12-31-2002	CIP of 10/062,264.
	6.	10/062,264	SPLX.P0062	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.
	7.	10/061,945	SPLX.P0063	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.
	8.	10/062,184	SPLX.P0064	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.
	9.	10/066,326	SPLX.P0110	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.
	10.	10/062,193	SPLX.P0112	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.

Examiner Signature		Date Considered	9/22/05
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Sheet	2 of 3

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>o</sup>
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	12.	Brandt et al., Circuit Multi-fault Diagnosis and Prediction Error Estimation Using a Committee of Bayesian Neural Networks, IEEE, Colloquium on Testing Mixed Signal Circuits and Systems, 23 October, 1997, pp. 7/1-7/7.	
	13.	Fertig, "Extracting Knowledge from Case Databases", Apr. 1991, IEEE Proceedings on Seventeenth Annual Northeast Bioengineering Conference, pp. 267-268.	
	14.	Hung et al., Machine Learning in Engineering Design - an Unsupervised Fuzzy Neural Network Case-based Learning Model, Dec. 1997, IEEE Proceeding, Intelligent Information System, pp. 156-160.	
	15.	Hunter, Knowledge Acquisition Planning for Inference from Large Databases, Jan. 1990, IEEE Proceeding of the 23th Annual Hawaii International Conference on System Sciences, vol. 2, pp. 35-44.	
	16.	Ida et al., Bayesian Analysis in Manufacturing Instrumentation for Test and Evaluation, IEEE, Conference record of 1993 Fourth Fifth Annual Conference of Electrical Engineering Problems and Plastics Industries, 27 April 1993, pp.4-13.	
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	23.	Ruping, S., Incremental Learning with Support Vector Machines, Dec. 2001, IEEE Proceedings of Internal Conference on Data Mining, pp. 641-642.	

Examiner Signature	<i>Tom Teska</i>	Date Considered	7/22/05
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NON PATENT LITERATURE DOCUMENTS		
<del>1-25</del>	24.	Suykens, Nonlinear Modelling and Support Vector Machines, May 2001, IEEE Proceedings of the 18 <sup>th</sup> Instrumentation and Measurement Technology Conference, vol 1, pp. 287-294.
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	28.	Yerramareddy et al., Creating and Using Models for Engineering Design A Machine-Learning Approach, Jun. 1992, IEEE Intelligent Systems, vol. 7, iss. 3, pp.52-59.
	29.	Zhang et al., Confidence Regions for Cascaded Neural Network Prediction in Power Markets, 2001 Power Engineering Society Winter Meeting, vol. 2, 28 January 2001, pp.533-538.
✓	30.	Zhang, C.X. et al., Floorplan Design Using a Hierarchical Neural Learning Algorithm, IEEE, 6/1991. pp. 2060-2063.

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<b>Title of Invention</b>	<b>Method and apparatus for creating an extraction model using Bayesian inference implemented with the Hybrid Monte Carlo method</b>																																																																													
<div>Application Number: 10/062196</div> <div>Confirmation Number: 9419</div> <div>First Named Applicant: Steven Teig</div> <div>Attorney Docket Number: SPLX.P0113</div> <div>Art Unit: 2123</div> <div>Examiner: Kevin J. Teska</div> <div>Search string: ( 4300196 or 4839823 or 5276632 or 5452224 or 5642296 or 5689621 or 5808919 or 5822218 or 5901063 or 5903469 or 6018623 or 6038338 or 6038383 or 6061508 or 6128768 or 6182269 or 6189131 or 6209123 or 6212492 or 6243653 or 6304836 or 6304837 or 6327556 or 6381555 or 6414498 or 6430729 or 6446027 or 6526549 or 6543035 or 6549854 or 6581195 or 6581198 or 6584456 or 6587997 or 6687887 or 6735748 or 20020010691 or 20020056070 or 20020075383 or 20030065535 or 20030236760 or 20040049751 ).pn.</div> <div><b>US Patent Documents</b></div> <div>Note: Applicant is not required to submit a paper copy of cited US Patent Documents</div> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Patent No.</th><th>Date</th><th>Patentee</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td>TU</td><td>1</td><td>4300196</td><td>1981-11-30</td><td>Lopresti</td><td></td><td></td><td></td></tr><tr><td></td><td>2</td><td>4839823</td><td>1986-06-13</td><td>Matsumoto</td><td></td><td></td><td></td></tr><tr><td></td><td>3</td><td>5276632</td><td>1994-01-04</td><td>Corwin et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>4</td><td>5452224</td><td>1995-09-19</td><td>Smith et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>5</td><td>5642296</td><td>1997-06-24</td><td>Saxena</td><td></td><td></td><td></td></tr><tr><td></td><td>6</td><td>5689621</td><td>1997-11-18</td><td>Salam et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>7</td><td>5808919</td><td>1998-09-15</td><td>Preist et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>8</td><td>5822218</td><td>1998-10-13</td><td>Moosa et al.</td><td></td><td></td><td></td></tr></tbody></table>							init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass	TU	1	4300196	1981-11-30	Lopresti					2	4839823	1986-06-13	Matsumoto					3	5276632	1994-01-04	Corwin et al.					4	5452224	1995-09-19	Smith et al.					5	5642296	1997-06-24	Saxena					6	5689621	1997-11-18	Salam et al.					7	5808919	1998-09-15	Preist et al.					8	5822218	1998-10-13	Moosa et al.			
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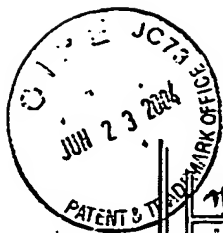


149	9	5901063	1999-05-04	Chang et al.	
	10	5903469	1999-05-11	Ho	
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	25	6414498	2002-07-02	Chen	B2
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	31	6581195	2003-06-17	Tanaka	B1
	32	6581198	2003-06-17	Teig et al.	B1
	33	6584456	2003-06-24	Dom et al.	B1
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	35	6687887	2004-02-03	Teig et al.	B1
	36	6735748	2004-05-11	Teig et al.	B1

## US Published Applications

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init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
149	1	20020010691	2002-01-24	Chen	A1		
	2	20020056070	2002-05-09	Tanaka	A1		
	3	20020075383	2002-06-20	Trobaugh et al.	A1		



<input checked="" type="checkbox"/>	4	20030065535	2003-04-03	Karlov et al.	A1
<input checked="" type="checkbox"/>	5	20030236760	2003-12-25	Nugent	A1
<input checked="" type="checkbox"/>	6	20040049751	2004-03-11	Teig et al.	A1

Signature

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<i>Sandra</i>	9/22/05